### **NAME**

CUTEST cifn – CUTEst tool to evaluate a problem function value.

## **SYNOPSIS**

```
CALL CUTEST_cifn( status, n, iprob, X, fn )
```

For real rather than double precision arguments, instead

CALL CUTEST\_cifn\_s( ... )

# **DESCRIPTION**

The CUTEST\_cifn subroutine evaluates the value of either the objective function or a constraint function of the problem decoded from a SIF file by the script sifdecoder at the point X, in the constrained minimization case. The problem under consideration is to minimize or maximize an objective function f(x) o ver all  $x \in R^n$  subject to general equations  $c_i(x) = 0$ ,  $(i \in 1, ..., m_E)$ , general inequalities  $c_i^l \le c_i(x) \le c_i^{u}$ ,  $(i \in m_E + 1, ..., m)$ , and simple bounds  $x^l \le x \le x^u$ . The objective function is group-partially separable and all constraint functions are partially separable.

#### **ARGUMENTS**

The arguments of CUTEST\_cifn are as follows

status [out] - integer

the outputr status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error,

n [in] - integer

the number of variables for the problem,

iprob [in] - integer

the number of the problem function to be considered. If iprob = 0, the value of the objective function will be evaluated, while if iprob = i > 0, that of the i-th constraint will be evaluated,

X [in] - real/double precision

an array which gives the current estimate of the solution of the problem,

fn [out] - real/double precision

the value of problem function iprob at X.

#### **AUTHORS**

I. Bongartz, A.R. Conn, N.I.M. Gould, D. Orban and Ph.L. Toint

## **SEE ALSO**

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads,

N.I.M. Gould, D. Orban and Ph.L. Toint,

Computational Optimization and Applications 60:3, pp.545-557, 2014.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,

N.I.M. Gould, D. Orban and Ph.L. Toint,

ACM TOMS, 29:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment,

I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint,

ACM TOMS, 21:1, pp.123-160, 1995.

sifdecoder(1)